

# Product/Process Change Notice - PCN 19\_0208 Rev. A

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

Note: Revised fields are indicated by a red field name. See Appendix B for revision history.

**PCN Title:** LTC4364 Notification of Die Revision Change

**Publication Date:** 28-Oct-2019

Effectivity Date: 30-Jan-2020 (the earliest date that a customer could expect to receive changed material)

**Revision Description:** Updating verbiage in PCN.

## **Description Of Change:**

The following enhancements have been made to the LTC4364-1 and LTC4364-2 product die:

- 1. EpiFETs were replaced with depletion-mode PMOS transistors. Associated thin film resistors were also adjusted. These changes improve manufacturing yield for the Vcc, SENSE and OUT pin currents in shutdown mode and the SHDN# pin current.
- 2. A third layer of metal was added for increased robustness.
- 3. Thin film resistors were added to the ESD cells of all high voltage pins to increase robustness.

#### **Reason For Change:**

The die changes were made to facilitate improvement in manufacturing yield and to increase robustness.

## Impact of the change (positive or negative) on fit, form, function & reliability:

This change does not impact on fit, form, function and reliability. Product specifications are not affected by these changes, and the datasheet remains unchanged.

Product Identification (this section will describe how to identify the changed material)

The new silicon can be identified with date code and lot traceability identification.

#### Summary of Supporting Information:

Qualification has been performed per industry standard test methods. The changes were qualified by performing characterization over the full operating junction temperature range and through rigorous engineering evaluation across a broad range of application conditions. In addition, the revised die has successfully passed 1000 hours High Temperature Operating Life stress test, and three separate fab lots have passed HAST with MSL1 preconditioning.

### **Supporting Documents**

Attachment 1: Type: Qualification Results Summary ADI\_PCN\_19\_0208\_Rev\_A\_rLTC4364\_RelData.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.					
Americas: PCN_Americas@analog.com	Europe:	<b>Japan:</b>	Rest of Asia:		
	PCN_Europe@analog.com	PCN_Japan@analog.com	PCN_ROA@analog.com		

Appendix A - Affected ADI Models						
Existing Parts - Product Family / Model Number (39)						
LTC4364/LTC4364CDE-1#PBF	LTC4364 / LTC4364CDE-1#TRPBF	LTC4364/LTC4364CDE-2#PBF	LTC4364/LTC4364CDE-2#TRPBF	LTC4364/LTC4364CMS-1#PBF		
LTC4364/LTC4364CMS-1#TRPBF	LTC4364/LTC4364CMS-2#PBF	LTC4364/LTC4364CMS-2#TRMPBF	LTC4364/LTC4364CMS-2#TRPBF	LTC4364/LTC4364CS-1#PBF		
LTC4364/LTC4364CS-1#TRPBF	LTC4364/LTC4364CS-2#PBF	LTC4364/LTC4364CS-2#TRPBF	LTC4364 / LTC4364HDE-1#PBF	LTC4364/LTC4364HDE-1#TRMPBF		
LTC4364/LTC4364HDE-1#TRPBF	LTC4364/LTC4364HDE-2#PBF	LTC4364/LTC4364HDE-2#TRPBF	LTC4364 / LTC4364HMS-1#PBF	LTC4364/LTC4364HMS-1#TRPBF		
LTC4364/LTC4364HMS-2#PBF	LTC4364/LTC4364HMS-2#TRPBF	LTC4364/LTC4364HS-1#PBF	LTC4364/LTC4364HS-1#TRPBF	LTC4364/LTC4364HS-2#PBF		
LTC4364/LTC4364HS-2#TRPBF	LTC4364 / LTC4364IDE-1#PBF	LTC4364/LTC4364IDE-1#TRPBF	LTC4364 / LTC4364IDE-2#PBF	LTC4364/LTC4364IDE-2#TRMPBF		
LTC4364/LTC4364IDE-2#TRPBF	LTC4364/LTC4364IMS-1#PBF	LTC4364/LTC4364IMS-1#TRPBF	LTC4364 / LTC4364IMS-2#PBF	LTC4364/LTC4364IMS-2#TRPBF		
LTC4364 / LTC4364IS-1#PBF	LTC4364/LTC4364IS-1#TRPBF	LTC4364 / LTC4364IS-2#PBF	LTC4364/LTC4364IS-2#TRPBF			

Appendix B - Revision History				
Rev	Publish Date	Effectivity Date	Rev Description	
Rev	11-Sep-2019	14-Dec-2019	Initial Release	
Rev. A	28-Oct-2019	30-Jan-2020	Updating verbiage in PCN.	

Analog Devices, Inc.

Docld:6879 Parent Docld:None Layout Rev:7